

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/512,629 NYBERG ET AL.	
		Examiner	Art Unit	Page 1 of 1 Chieh M Fan 2634

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,887,022	03-1999	Lee et al.	375/132
	B	US-6,128,327	10-2000	Bird et al.	375/132
	C	US-6,549,784	04-2003	Kostic et al.	455/501
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10065648 A	03-1998	Japan	SANO, KOICHI	H04J 13/06
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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